SNAP™-X

SNAP-X is a powerful metrology software program with a simple user interface. Three functions allow for a range of different uses – from fast walk-up measurement, to advanced GD&T analysis.

- **Compare –**
  The most basic measurement. Zoom Anywhere technology instantly zooms the image anywhere in the wide field of view to measure small features instantly.

- **Measure –**
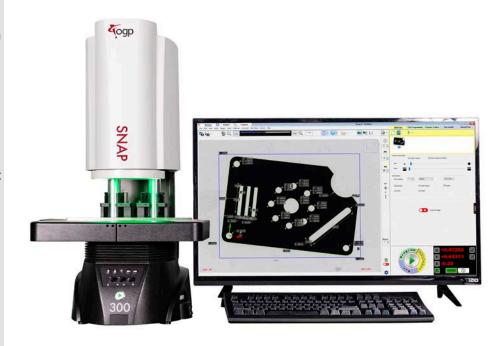 Intermediate, detailed measurement tasks. SnapShot identifies and measures features instantly - without programming.

- **Analyze (optional) –**
  Address more complex GD&T requirements. Integrated reporting allows for quick and easy output of measurements.
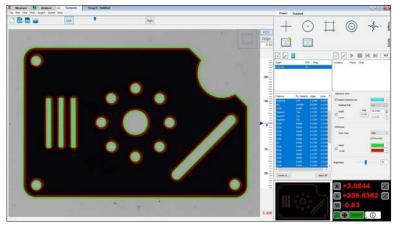
- **Multi-System Capable –**
  Standard of all SNAP, c-vision™, and Contour Projectors® with optional VidiProbe automatic video measurement package.

Powerful Metrology Software with a Simple Interface for Ease of Use
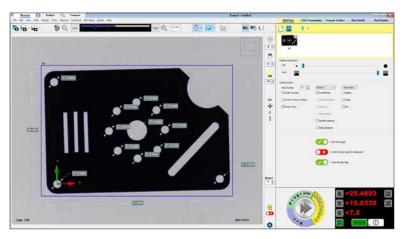

Scan for more SNAP-X information

Compare

The most basic measurement (Pass/Fail). No variable data, a widely accepted method of quickly assessing part acceptability.

The Compare Tab is selected, a CAD file is imported, and the operator is able to fit the part image to the CAD overlay on the monitor.

This allows the user the ability to use effective surface illumination, easy to maintain CAD overlays, and the option to change mag with the same overlay – all within a smaller footprint versus a traditional optical comparator.
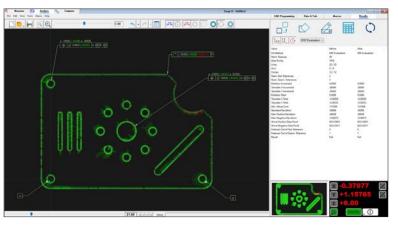

Measure

With the Measure Tab selected, various measurement tasks can be performed, depending on the mode selected:

SnapShot™ Mode: Place the part on the stage, press GO. The image is scanned and Feature Extracts all discernable features. Images may be viewed with no further action, or the features can be turned into measured steps for a program.

Program Mode: Measurements can be taken, and programs can be created. An operator creates a program from extracted features of SNAPshot Mode by making the measurements as usual with a video measurement system, or from a CAD file of the part.

Run Mode: A pre-set selection of a desired routines is available for the operator to select.

Analyze (optional)

Users have the ability to address more complex GD&T requirements such as profile, true position of features when datum features of size allow mobility on the feature and the datums.

The display and reporting capabilities with Analyze provide both graphical, color coded whiskers of deviation, and GD&T callouts on the part CAD.

Analyze works seamlessly with SNAP-X Measure functions

SNAP-X metrology software is compatable with:

- **SNAP** Large Field-of-View Digital Measuring Systems
- **c-vision**™ Video Contour Projector® Systems
- **Contour Projector Systems** with optional **VidiProbe** automatic video measurement package

Confidence. When Results Matter.™